substrate, and an elongate section extending from the portion to the contact region, the elongate section resiliently bending upon depression of the contact region towards the substrate, wherein the contact region of two adjacent resilient contact structures are spaced differently than the terminals of the adjacent resilient contact structures and wherein respective ones of the second set of terminals are coupled to corresponding ones of the first set of terminals; and

a second set of resilient contact structures, each having a portion attached to a respective one of the terminals of the second set of terminals, a contact region distant from the substrate, and an elongate section extending from the portion to the contact region, the elongate section resiliently bending upon depression of the contact region towards the substrate.

45. (Amended) Probe Card Assembly, comprising:

a probe card having a first surface, a second surface and a plurality of contact terminals on the first surface thereof;

a space transformer having a first surface, a second surface, a plurality of contact pads disposed on the second surface thereof, and a first plurality of resilient [freestanding] freestanding contact structures [mounted adjacent to and] mounted adjacent to and extending from the first surface thereof;

wherein the plurality of contact pads are connected to the plurality of contact terminals of the probe card.

52. (Amended) Probe Card Assembly, according to claim 45, wherein:

the contact pads are disposed at a first pitch on the second surface of the space transformer;

the first plurality of resilient contact structures [[are] each having a contact region, the contact region] each having a contact region, the contact region disposed at a second pitch [[on the first surface of the space transformer]]; and